THE INFLUENCE OF A FOCUSED LOAD ON FORMATION OF X-RAY THICKNESS INTENSITY OSCILLATIONS

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S u m m a r y

The influence of weak and strong distortions caused by a focused load on formation of moire intensity oscillations in wedge-shaped Si and Ge crystals is investigated experimentally and by a numerical solution of the Takagi equations. Scattering processes that stipulate a bending and focusing (defocusing) of X-ray trajectories influence the formation of moire fringes in the case of weak strains and the processes of interbranch scattering ¯ in the case of strong strains.